JOURNAL OF ICT STANDARDIZATION

Volume 6, No. 3 (September 2018)

JOURNAL OF ICT STANDARDIZATION

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Objectives

- Bring papers on new developments, innovations and standards to the readers
- Cover pre-development, including technologies with potential of becoming a standard, as well as developed/deployed standards
- Publish on-going work including work with potential of becoming a standard technology
- Publish papers giving explanation of standardization and innovation process and the link between standardization and innovation
- Publish tutorial type papers giving new comers a understanding of standardization and innovation

Aims

- The aim of this journal is to publish standardized as well as related work making "standards" accessible to a wide public – from practitioners to new comers.
- The journal aims at publishing in-depth as well as overview work including papers discussing standardization process and those helping new comers to understand how standards work.

Scope

- Bring up-to-date information regarding standardization in the field of Information and Communication Technology (ICT) covering all protocol layers and technologies in the field.

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Editorial Foreword

We present 5 papers in this issue of the journal. Short version of first 3 papers were published in ITU Kaleidoscope 2017; extended version with new results was submitted to the journal. All extended and directly submitted papers were thoroughly reviewed before acceptance for publication.

Papers are listed below:

1. Towards informing human-centric ICT standardization for data-driven societies
   Mamello Thinyane (Institute on Computing and Society (UNU-CS), Macau – SAR)
2. Sparse data enrichment by context oriented model reduction techniques in manufacturing industry with an example laser drilling process
   You Wang (NLD of RWTH Aachen University, Steinbachstraße, Germany)
   Hasan Tercan (IMA of RWTH Aachen University, Dennwartstraße, Germany)
   Torsten Hermanns (Fraunhofer Institute for Laser Technology, Steinbachstraße, Germany)
   Thomas Thiele (IMA of RWTH Aachen University, Dennwartstraße, Germany)
   Tobias Meisen (IMA of RWTH Aachen University, Dennwartstraße, Germany)
   Sabina Jeschke (IMA of RWTH Aachen University, Dennwartstraße, Germany)
   Wolfgang Schulz (Fraunhofer Institute for Laser Technology, Steinbachstraße, Germany)
3. Capability Maturity Models as a Means to Standardize Sustainable Development Goals Indicators Data Production
   Ignacio Marcovecchio (Institute on Computing and Society (UNU-CS), Macau)

Mamello Thinyane (Institute on Computing and Society (UNU-CS), Macau)
Elsa Estevez (Instituto de Ciencias e Ingeniería de la Computación, CONICET, Argentina)
Pablo Fillottrani (Universidad Nacional del Sur, Argentina)

4. Mobile Subscriber Profile data Privacy Breach via 4G Diameter Interconnection
   Silke Holtmanns (Nokia Bell Labs, Security Research, Karakaari 3, 02610 Espoo, Finland)
   Ian Oliver (Nokia Bell Labs, Security Research, Karakaari 3, 02610 Espoo, Finland)
   Yoan Miche (Nokia Bell Labs, Security Research, Karakaari 3, 02610 Espoo, Finland)
5. Experiences in Trusted Cloud Computing
   Ian Oliver (Nokia Bell Labs, Security Research, Karakaari 3, 02610 Espoo, Finland)
   Silke Holtmanns (Nokia Bell Labs, Security Research, Karakaari 3, 02610 Espoo, Finland)
   Shankar Lal (Nokia Bell Labs, Security Research, Karakaari 3, 02610 Espoo, Finland)

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